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FDP5N60NZ / FDPF5N60NZ N-Channel UniFETTM II MOSFET 600 V, 4.5 A, 2.0 Ω

Features

- $R_{DS(on)}$ = 1.65 Ω (Typ.) @ V_{GS} = 10 V, I_D = 2.25 A
- Low Gate Charge (Typ. 10 nC)
- Low C_{rss} (Typ. 5 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Improved Capability
- RoHS Compliant

Applications

- LCD / LED / PDP TV
- Lighting
- Uninterruptible Power Supply
- AC-DC Power Supply

Description

UniFETTM II MOSFET is Fairchild Semiconductor's high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on-state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.



November 2013

GDS TO-220 GDS

TO-220F

MOSFET Maximum Ratings T_C = 25°C unless otherwise noted.

Symbol		FDP5N60NZ	FDPF5N60NZ	Unit			
V _{DSS}	Drain to Source Voltage			6	V		
V _{GSS}	Gate to Source Voltage			±	V		
ID	Desire Current	- Continuous (T _C = 25 ^o C)		4.5	4.5*		
	Drain Current	- Continuous (T _C = 100 ^o C)		2.7	2.7*	A	
I _{DM}	Drain Current	- Pulsed	- Pulsed (Note 1)		18*	Α	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		175		mJ		
AR	Avalanche Current		(Note 1)	4.5		Α	
E _{AR}	Repetitive Avalanche Energy		(Note 1)	10		mJ	
dv/dt	MOSFET dv/dt			2	V/ns		
	Peak Diode Recovery dv/dt		(Note 3)	10		V/ns	
P _D	Dower Dissinction	(T _C = 25°C)		100	33	W	
	Power Dissipation	- Derate above 25°C	- Derate above 25°C		0.27	W/ºC	
T _J , T _{STG}	Operating and Storage Temperature Range			-55 to	°C		
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 Seconds			3	°C		
Dran current	limited by maximum junction ter	mperature					

Thermal Characteristics

Symbol	Parameter	FDP5N60NZ	FDPF5N60NZ	Unit
$R_{ extsf{ heta}JC}$	Thermal Resistance, Junction to Case, Max.	1.25	3.75	°C/W
$R_{ hetaJA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	62.5	0/10

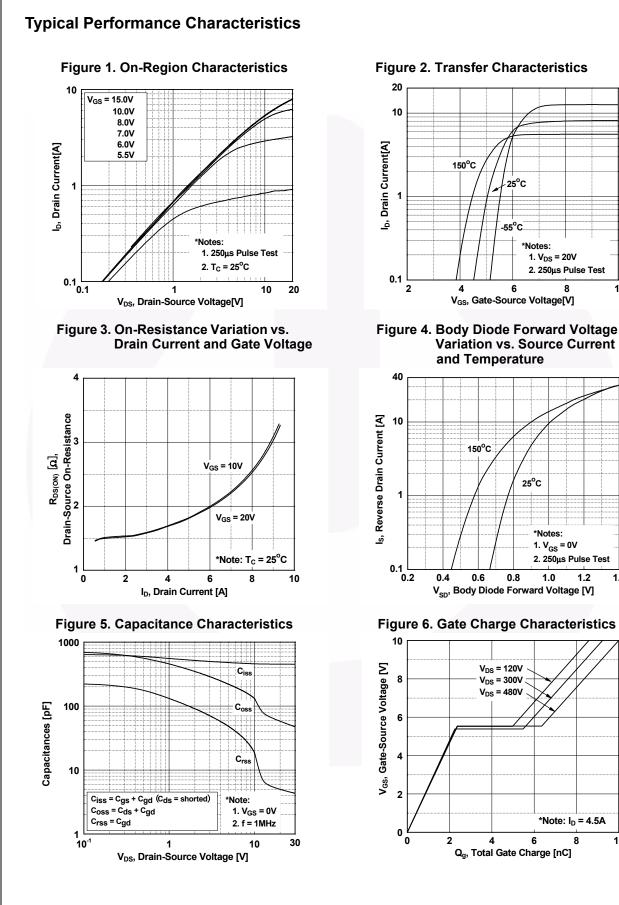
nber	Top Mark	Package	Packing Method	Reel Size	e Ta	ape Width	Qu	Quantity	
FDP5N60NZ FDP5N60NZ		TO-220	Tube	N/A		N/A	50 units		
FDPF5N60NZ FDPF5N60NZ T		TO-220F	Tube	N/A	N/A		50 units		
Chara	cteristics T _C = 25°C	unless othe	erwise noted.						
	Parameter		Test Condition	S	Min.	Тур.	Max.	Unit	
teristics	i								
Drain to	Source Breakdown Voltage	e l _D	= 250 μA, V _{GS} = 0 V		600	-	-	V	
	• •	I _D :	$I_D = 250 \mu\text{A}$, Referenced to 25°C		-	0.6	-	V/ºC	
Zero Gat	e Voltage Drain Current					-	1 10	μA	
Gate to E	ate to Body Leakage Current		$V_{GS} = \pm 25 \text{ V}, V_{DS} = 0 \text{ V}$		-	-	±10	μA	
oristics								_	
1		Va	a = V_a a = 250 uA		3.0		5.0	V	
								Ω	
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1									
· ·		Vr	V _{DS} = 25 V, V _{GS} = 0 V, f = 1 MHz		-			pF	
						50		pF	
					-	-		pF	
			V_{DS} = 480 V, I _D = 4.5 A, V _{GS} = 10 V		-	-	13	nC	
		VG			-	-	-	nC	
Gate to D	Drain "Miller" Charge			(Note 4)	-	4	-	nC	
Charact	eristics								
Turn-On Delay Time		Vr	V _{DD} = 300 V, I _D = 4.5 A,		-	15	40	ns	
Turn-On	Rise Time		V_{GS} = 10 V, R_G = 25 Ω		-	20	50	ns	
Turn-Off	Delay Time				-	35	80	ns	
Turn-Off	Fall Time			(Note 4)	-	20	50	ns	
ce Diod	e Characteristics								
Maximum Continuous Drain to Source Diode Forward Current					-	-	4.5	Α	
		iode Forwar	d Current		-	-	18	Α	
Drain to §			V _{GS} = 0 V, I _{SD} = 4.5 A		-	-	1.4	V	
Reverse	Recovery Time	-	$V_{GS} = 0 V, I_{SD} = 4.5 A,$ $dI_F/dt = 100 A/\mu s$		-	230		ns	
Reverse	Recovery Charge	dl _F			-	0.9	-	μC	
	Charac Chara eristics Drain to 3 Breakdoo Coefficie Zero Gat Gate to E eristics Gate Thr Static Dra Forward naracter Input Car Output C Reverse Total Gat Gate to E Character Character Character Turn-On Turn-On Turn-Off Turn-Off Turn-Off Turn-Off Maximum Maximum Drain to S Reverse	ONZ FDP5N60NZ SONZ FDPF5N60NZ Characteristics T _C = 25°C Parameter eristics Drain to Source Breakdown Voltage Breakdown Voltage Temperature Coefficient Zero Gate Voltage Drain Current Gate to Body Leakage Current eristics Gate Threshold Voltage Static Drain to Source On Resistand Forward Transconductance haracteristics Input Capacitance Output Capacitance Output Capacitance Total Gate Charge at 10V Gate to Drain "Miller" Charge Characteristics Turn-On Delay Time Turn-On Rise Time Turn-Off Delay Time Turn-Off Fall Time Ce Diode Characteristics Maximum Continuous Drain to Source D	ONZ FDP5N60NZ TO-220 SONZ FDPF5N60NZ TO-220F Characteristics T _C = 25°C unless other Parameter Image: Source Breakdown Voltage Ip Breakdown Voltage Temperature Ip Coefficient Vp Zero Gate Voltage Drain Current Vp Vp Gate to Body Leakage Current Vp Gate to Body Leakage Current Vp Vp Gate Threshold Voltage Vp Gate Threshold Voltage Vp Vp Gate Threshold Voltage Vp Gate Threshold Voltage Vp Vp Gate Threshold Voltage Vp Gate Threshold Voltage Vp Vp Gate Threshold Voltage Vp Forward Transconductance Vp Vp Input Capacitance Vp Gate to Source Gate Charge Vp Vp Gate to Drain "Miller" Charge Vp Vp Characteristics Turn-On Delay Time Vp Vp <t< td=""><td>DNZFDP5N60NZTO-220TubeSONZFDPF5N60NZTO-220FTubeCharacteristicsParameterTest ConditioneristicsDrain to Source Breakdown Voltage$I_D = 250 \ \mu$A, $V_{GS} = 0 \ V$Breakdown Voltage Temperature Coefficient$I_D = 250 \ \mu$A, ReferencedZero Gate Voltage Drain Current$V_{DS} = 600 \ V, V_{GS} = 0 \ V$Gate to Body Leakage Current$V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$Gate Threshold Voltage$V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$Gate Threshold Voltage$V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$Gate Threshold Voltage$V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$Gate Threshold Voltage$V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$Input Capacitance$V_{DS} = 20 \ V, I_D = 2.25 \ A$Forward Transconductance$V_{DS} = 20 \ V, I_D = 2.25 \ A$Input Capacitance$V_{DS} = 25 \ V, V_{GS} = 0 \ V, I_S = 20 \ V, I_D = 4.5 \ A, V_{GS} = 10 \ V, R_G = 25 \ \Omega$CharacteristicsTurn-On Delay TimeTurn-Off Delay Time$V_{DD} = 300 \ V, I_D = 4.5 \ A, V_{GS} = 10 \ V, R_G = 25 \ \Omega$Turn-Off Fall Time$V_{GS} = 0 \ V, R_G = 25 \ \Omega$Maximum Continuous Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentDrain to Source Diode Forward VoltageV_{GS} = 0 V, I_SD = 4.5 \ A, Reverse Recovery TimeV_{GS} = 0 V, I_SD = 4.5 \ A, Reverse Recovery Time</td><td>DNZFDP5N60NZTO-220TubeN/A60NZFDPF5N60NZTO-220FTubeN/ACharacteristicsPraneterTo-220FTubeN/ACharacteristicsDrain to Source Breakdown VoltageID$= 250 \ \mu$A, VGS = 0 VBreakdown Voltage TemperatureID$= 250 \ \mu$A, Referenced to 25°CCoefficientVDS = 600 V, VGS = 0 VZero Gate Voltage Drain CurrentVDS = 480 V, TC = 125^{\circ}CGate to Body Leakage CurrentVGS = $\pm 25 \ V, DS = 0 \ V$eristicsGate to Body Leakage CurrentVGS = $\pm 25 \ V, DS = 0 \ V$Static Drain to Source On ResistanceVDS = 20 V, ID = 250 μAStatic Drain to Source On ResistanceVDS = 25 V, VGS = 0 V,f = 1 MHzReverse Transfer CapacitanceVDS = 25 V, VGS = 0 V,f = 1 MHzTum-On Delay TimeVDS = 480 V, ID = 4.5 A,Qate to Drain "Miller" ChargeVDS = 480 V, ID = 4.5 A,CharacteristicsVDS = 10 VTurn-On Blay TimeVDS = 10 V,Turn-Off Belay TimeVDS = 10 V,Turn-Off Fall TimeVGS = 10 V, RG = 25 \OmegaColode CharacteristicsMaximum Continuous Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward CurrentMaximum Pulsed Drain to Source Diode Forward Current</td><td>DNZFDP5N60NZTO-220TubeN/A60NZFDPFSN60NZTO-220FTubeN/ACharacteristicsParameterTest ConditionsMin.eristicsDrain to Source Breakdown 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Voltage & I_D = 250 \ \mu A, V_{GS} = 0 \ V & 600 & - \\ \hline Breakdown Voltage Temperature & I_D = 250 \ \mu A, Referenced to 25°C & - & 0.6 \\ \hline Coefficient & V_{DS} = 600 \ V, V_{GS} = 0 \ V & - & - & - \\ \hline V_{DS} = 480 \ V, \ T_C = 125°C & - & - & \\ \hline Gate to Body Leakage Current & V_{GS} = V_{DS}, \ I_D = 250 \ \mu A & 3.0 & - \\ \hline eristics & \\ \hline Gate Threshold Voltage & V_{GS} = V_{DS}, \ I_D = 250 \ \mu A & 3.0 & - \\ \hline Static Drain to Source On Resistance & V_{GS} = 10 \ V, \ I_D = 2.25 \ A & - & 1.65 \\ \hline Forward Transconductance & V_{DS} = 20 \ V, \ I_D = 2.25 \ A & - & 5 \\ \hline naracteristics & \\ \hline Input Capacitance & V_{DS} = 25 \ V, \ V_{CS} = 0 \ V, \ - & - & 5 \\ \hline naracteristics & \\ \hline Input Capacitance & V_{DS} = 25 \ V, \ V_{CS} = 0 \ V, \ - & - & 5 \\ \hline Cotal Gate Charge at 10V & V_{DS} = 480 \ V, \ I_D = 4.5 \ A, \ - & 10 \\ \hline Gate to Drain "Miller" Charge & V_{CS} = 10 \ V, \ R_G = 20 \ V, \ R_G = 10 \ V, \ R$</td><td>$\begin{tabular}{ c c c c c c } \hline FDP5N60NZ & TO-220 & Tube & N/A & N/A & S0 \\ \hline FDP5N60NZ & TO-220F & Tube & N/A & N/A & S0 \\ \hline FDP5N60NZ & TO-220F & Tube & N/A & N/A & S0 \\ \hline CharaCteristics & &$</td></t<>	DNZFDP5N60NZTO-220TubeSONZFDPF5N60NZTO-220FTubeCharacteristicsParameterTest ConditioneristicsDrain to Source Breakdown Voltage $I_D = 250 \ \mu$ A, $V_{GS} = 0 \ V$ Breakdown Voltage Temperature Coefficient $I_D = 250 \ \mu$ A, ReferencedZero Gate Voltage Drain Current $V_{DS} = 600 \ V, V_{GS} = 0 \ V$ Gate to Body Leakage Current $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Gate Threshold Voltage $V_{GS} = \pm 25 \ V, V_{DS} = 0 \ V$ Input Capacitance $V_{DS} = 20 \ V, I_D = 2.25 \ A$ Forward Transconductance $V_{DS} = 20 \ V, I_D = 2.25 \ A$ Input Capacitance 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480 \ V, \ T_C = 125°C & - & - & \\ \hline Gate to Body Leakage Current & V_{GS} = V_{DS}, \ I_D = 250 \ \mu A & 3.0 & - \\ \hline eristics & \\ \hline Gate Threshold Voltage & V_{GS} = V_{DS}, \ I_D = 250 \ \mu A & 3.0 & - \\ \hline Static Drain to Source On Resistance & V_{GS} = 10 \ V, \ I_D = 2.25 \ A & - & 1.65 \\ \hline Forward Transconductance & V_{DS} = 20 \ V, \ I_D = 2.25 \ A & - & 5 \\ \hline naracteristics & \\ \hline Input Capacitance & V_{DS} = 25 \ V, \ V_{CS} = 0 \ V, \ - & - & 5 \\ \hline naracteristics & \\ \hline Input Capacitance & V_{DS} = 25 \ V, \ V_{CS} = 0 \ V, \ - & - & 5 \\ \hline Cotal Gate Charge at 10V & V_{DS} = 480 \ V, \ I_D = 4.5 \ A, \ - & 10 \\ \hline Gate to Drain "Miller" Charge & V_{CS} = 10 \ V, \ R_G = 20 \ V, \ R_G = 10 \ V, \ R$	$\begin{tabular}{ c c c c c c } \hline FDP5N60NZ & TO-220 & Tube & N/A & N/A & S0 \\ \hline FDP5N60NZ & TO-220F & Tube & N/A & N/A & S0 \\ \hline FDP5N60NZ & TO-220F & Tube & N/A & N/A & S0 \\ \hline CharaCteristics & 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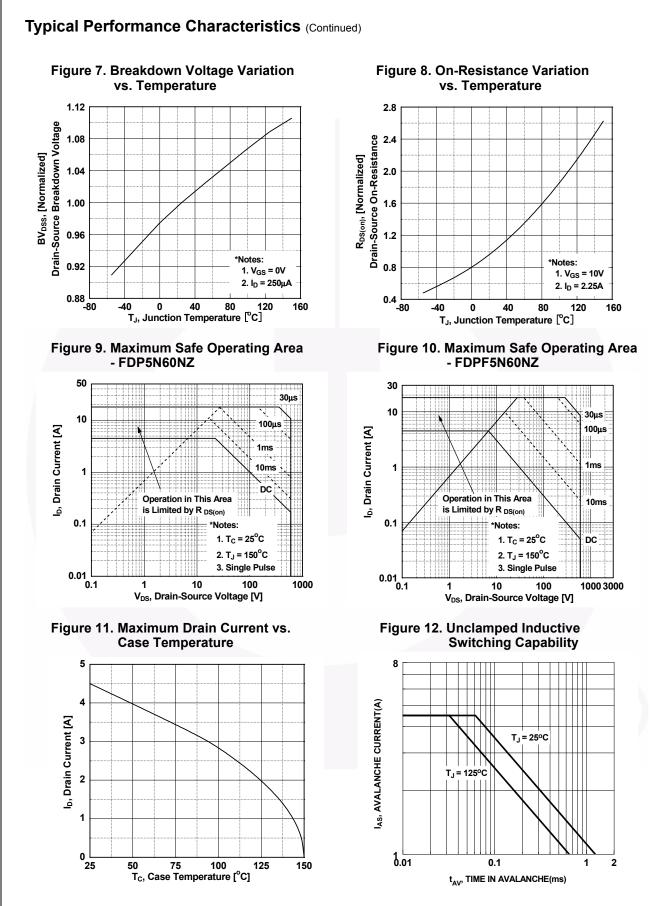


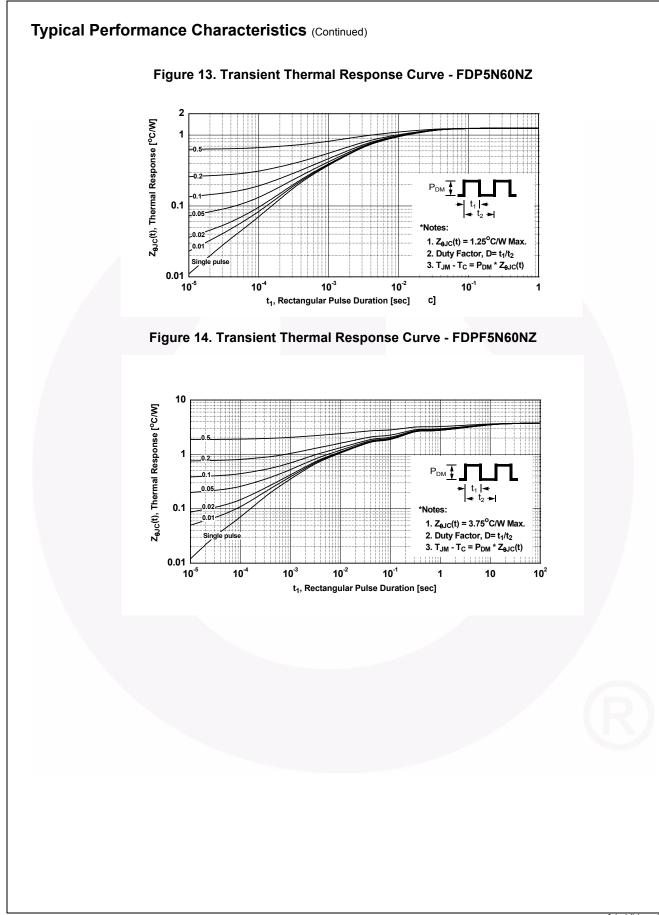
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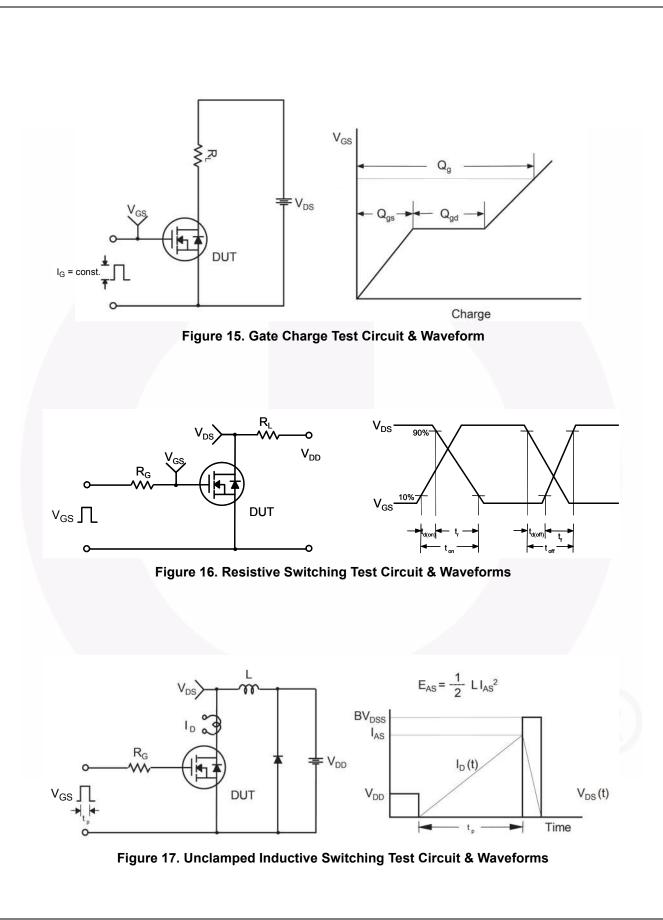
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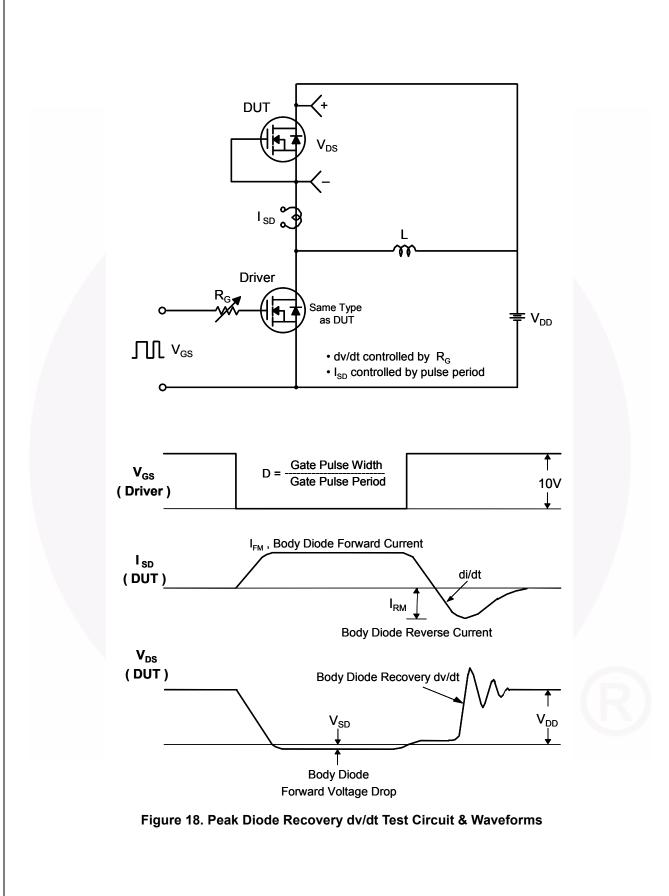


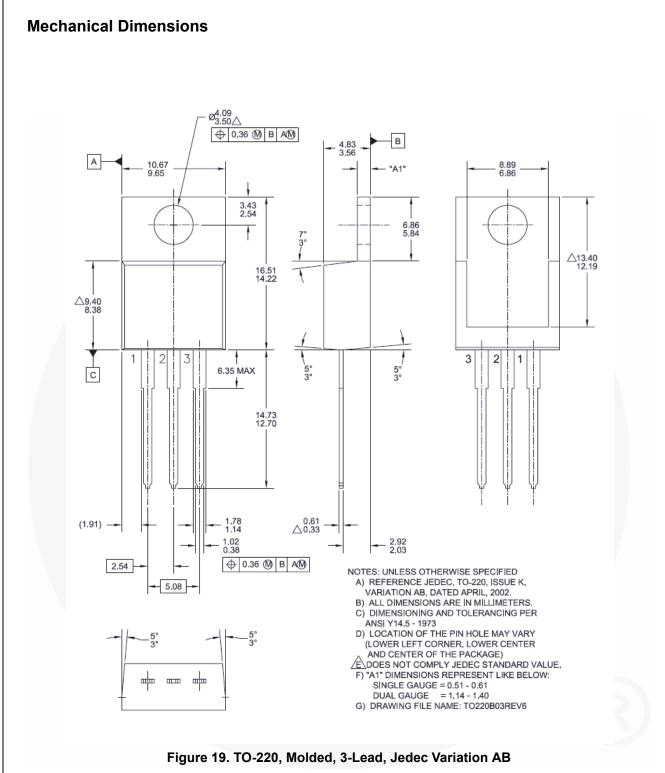




FDP5N60NZ / FDPF5N60NZ — N-Channel UniFETTM II MOSFET

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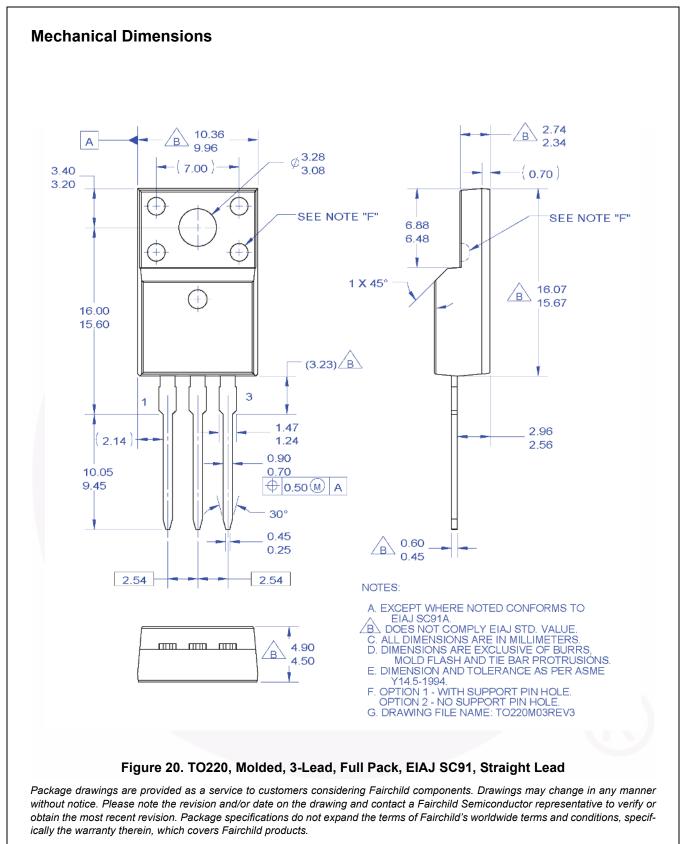


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Datasheet Identification	Product Status	Definition				
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